NAME

CUTEST ccifg - CUTEst tool to evaluate a single constraint function value and possibly its gradient.

SYNOPSIS

CALL CUTEST_ccifg(status, n, icon, X, ci, GCI_val, grad)

DESCRIPTION

The CUTEST_ccifg subroutine evaluates the value of a particular constraint function of the problem decoded from a SIF file by the script *sifdecoder* at the point X, and possibly its gradient in the constrained minimization case. The problem under consideration is to minimize or maximize an objective function f(x) over all $x \in R^n$ subject to general equations $c_i(x) = 0$, $(i \in 1, ..., m_E)$, general inequalities $c_i^l(x) \le c_i^l(x)$, $(i \in m_E + 1, ..., m)$, and simple bounds $x^l \le x \le x^u$. The objective function is group-partially separable and all constraint functions are partially separable.

ARGUMENTS

The arguments of CUTEST_ccifg are as follows

status [out] - integer

the outputr status: 0 for a successful call, 1 for an array allocation/deallocation error, 2 for an array bound error, 3 for an evaluation error.

n [in] - integer

the number of variables for the problem,

icon [in] - integer

the index of the constraint function to be evaluated,

X [in] - real/double precision

an array which gives the current estimate of the solution of the problem,

ci [out] - real/double precision

the value of constraint function icon at X.

GCI_val [out] - real/double precision

an array which gives the gradient of constraint function icon evaluated at X,

grad [in] - logical

a logical variable which should be set .TRUE. if the gradient of the constraint functions are required and .FALSE, otherwise.

AUTHORS

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SEE ALSO

CUTEst: a Constrained and Unconstrained Testing Environment with safe threads,

N.I.M. Gould, D. Orban and Ph.L. Toint,

Technical Report, Rutherford Appleton Laboratory, 2013.

CUTEr (and SifDec): A Constrained and Unconstrained Testing Environment, revisited,

N.I.M. Gould, D. Orban and Ph.L. Toint,

ACM TOMS, 29:4, pp.373-394, 2003.

CUTE: Constrained and Unconstrained Testing Environment, I. Bongartz, A.R. Conn, N.I.M. Gould and Ph.L. Toint, ACM TOMS, **21**:1, pp.123-160, 1995.

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